

**Search Notes**

Application/Control No.

10/563,576

Examiner

David Mis

Applicant(s)/Patent under  
Reexamination

EYRIES ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
332	100-102	7/12/2006	DM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
USPGPUB	(see history)	7/12/2006	DM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR